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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/617,817	07/14/2003	Toshio Teraishi	03DCOAI030 5232	
26071 7590 08/24/2007 JUNICHI MIMURA OKI AMERICA INC. 1101 14TH STREET, N.W. SUITE 555			EXAMINER	
			VELEZ, ROBERTO	
			ART UNIT	PAPER NUMBER
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

· · · · · · · · · · · · · · · · · · ·	Application No.	Applicant(s)			
	10/617,817	TERAISHI, TOSHIO			
Office Action Summary	Examiner	Art Unit			
•	Roberto Velez	2829			
The MAILING DATE of this communication app	•	<u></u>			
Period for Reply		,			
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period v  - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tir will apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).			
Status	•				
1) Responsive to communication(s) filed on 01 Ju	<u>une 2007</u> .				
,					
	☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is				
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims					
4) ☐ Claim(s) 1-19 is/are pending in the application.  4a) Of the above claim(s) 4-11 and 16-19 is/are  5) ☐ Claim(s) is/are allowed.  6) ☐ Claim(s) 1-3 and 12-15 is/are rejected.  7) ☐ Claim(s) is/are objected to.  8) ☐ Claim(s) are subject to restriction and/o	e withdrawn from consideration.				
Application Papers					
9) ☐ The specification is objected to by the Examine 10) ☑ The drawing(s) filed on 01 June 2007 is/are: a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) ☐ The oath or declaration is objected to by the Example 2015.	)⊠ accepted or b)□ objected to drawing(s) be held in abeyance. Se tion is required if the drawing(s) is ob	e 37 CFR 1.85(a). ojected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119	•				
a) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Burea * See the attached detailed Office action for a list	ts have been received. ts have been received in Applicat rity documents have been receiv u (PCT Rule 17.2(a)).	tion No ed in this National Stage			
Attachment(s)	•				
1) Notice of References Cited (PTO-892)	4) 🔲 Interview Summar				
<ul> <li>2) Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>3) Information Disclosure Statement(s) (PTO/SB/08)</li> <li>Paper No(s)/Mail Date 07/14/2003</li> </ul>	Paper No(s)/Mail D 5) Notice of Informal 6) Other:				

#### **DETAILED ACTION**

## Response to Arguments

1. Applicant's arguments with respect to claims 1-3 and 12-15 have been considered but are moot in view of the new ground(s) of rejection.

## Claim Objections

- Claims 12-15 are objected to because of the following informalities: Claim 12, Ln
   should recite "single test signal" instead of "ingle test signal". Appropriate correction is required.
- 3. Claims 13-15 depending from claim 12 are objected for the same reason.

# Claim Rejections - 35 USC § 112

4. The following is a quotation of the first paragraph of 35 U.S.C. 112:

The specification shall contain a written description of the invention, and of the manner and process of making and using it, in such full, clear, concise, and exact terms as to enable any person skilled in the art to which it pertains, or with which it is most nearly connected, to make and use the same and shall set forth the best mode contemplated by the inventor of carrying out his invention.

5. Claims 1-3 and 12-15 are rejected under 35 U.S.C. 112, first paragraph, as failing to comply with the written description requirement. The claim(s) contains subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed, had possession of the claimed invention. Claim 1, Ln 5, recites the claim limitation "which outputs a test result only". This limitation was not found in the written description. Applicant is welcomed to point out where in the Specification the Examiner could find support for this limitation. Claim 12, Ln 12-13, recites the claim limitation "the single test signal output lead outputting

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a test signal only". This limitation was not found in the written description.

Applicant is welcomed to point out where in the Specification the Examiner could find support for this limitation.

6. Claims 2-3 and 13-15 depending from claims 1 or 12 are rejected for the same reason.

# Claim Rejections - 35 USC § 103

- 7. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 8. Claims 12-15 are rejected under 35 U.S.C. 103(a) as being unpatentable over Berlin et al. (US Pat. 7,132,841) in view of Van Brunt (US Pat. 4,357,703).

Regarding claim 12, *Berlin et al.* shows (Fig. 1b) a chip carrier [23], which has a user area (area where 25 and 31 are positioned) and a non-user area (area where 27, 29, 35, 33 are positioned), for mounting a LSI chip in the user area, comprising: a plurality of leads [25 on the left side], each of which is formed in the user area (area where 25 and 31 are positioned) and extended in a first direction to the non-user area (area where 27, 29, 35, 33 are positioned); a plurality of leads [25 on the right side], each of which is formed in the user area (area where 25 and 31 are positioned) and extended in a second direction, which is different from the first direction, to the non-user area (area where 27, 29, 35, 33 are positioned); a single test signal input lead (either one of 31), which is

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formed in the user area (area where 25 and 31 are positioned) and extended in the first direction to the non-user area (area where 27, 29, 35, 33 are positioned); and a single test signal output lead (either one of 31), which is formed in the user area (area where 25 and 31 are positioned) and extended in the first direction to the non-user area (area where 27, 29, 35, 33 are positioned).

Berlin et al. fails to specify input leads, output leads, a single test signal input lead receiving a test signal for testing an internal circuit formed in the LSI chip and a single test signal output lead outputting a test signal only. However, Van Brunt shows (Fig. 1) input leads [12], output leads [30], a single test signal input lead [21] receiving a test signal for testing an internal circuit [11] formed in the LSI chip (Col. 4, Ln 1-5) and a single test signal output lead [33] outputting a test signal only (Col. 4, Ln 12-19).

It would have been obvious to one of ordinary skill in the art at the time the invention was made to incorporate the teachings of *Van Brunt* into the device of *Berlin et al.* by having and assigning input leads, output leads, a single test signal input lead and a single test signal output lead in the chip carrier to match a LSI chip pattern. The ordinary artisan would have been motivated to modify *Berlin et al.* in the manner set forth above for the purpose of performing dynamic testing of complex logic modules in an efficient and faster manner.

Regarding claim 13, the combination of *Berlin et al.* and *Van Brunt* discloses everything as claimed above in claim 12; in addition, *Berlin et al.* 

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shows (Fig. 1b) a plurality of test pads [35] formed in the non-user area (area where 27, 29, 35, 33 are positioned).

Berlin et al. fails to disclose each of which is connected to one of the output leads. However, Van Brunt shows (Fig. 1) a test pad (will be connected to 33) connected (electrically connected) to each one of the output leads [30].

It would have been obvious to one of ordinary skill in the art at the time the invention was made to incorporate the teachings of *Van Brunt* into the device of *Berlin et al.* by having a plurality of test pads formed in the non-user area, each of which is connected to one of the output leads. The ordinary artisan would have been motivated to modify *Berlin et al.* in the manner set forth above for the purpose of having alternate paths to transmit test signals.

Regarding claim 14, the combination of *Berlin et al.* and *Van Brunt* discloses everything as claimed above in claim 12.

The combination of *Berlin et al.* and *Van Brunt* fails to disclose wherein a width of the test signal output lead is wider than that of each output lead.

It would have been obvious to have a wider test signal output lead than that of each output lead for the purpose of minimizing alignment error tolerance while making contact between the test signal output lead of the carrier and the test signal output terminal of the LSI chip.

Regarding claim 15, the combination of **Berlin et al.** and **Van Brunt** discloses everything as claimed above in claim 12.

The combination of *Berlin et al.* and *Van Brunt* fails to disclose wherein a test signal input lead and the test signal output lead sandwich the input leads.

It would have been obvious to sandwich the input leads with the test signal input lead and the test signal output lead for the purpose of making easier to manufacture.

### Conclusion

- 9. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).
- 10. A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.
- 11. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Roberto Velez whose telephone number is 571-

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272-8597. The examiner can normally be reached on Monday-Friday 8:00am-4:30 pm.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on 571-272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Roberto Velez Patent Examiner

HA TRAN NGUYEN

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SUPERVISORY PATENT EXAMINER

8/20/7